Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination
10/687,643	MINO, TETSUYA
Examiner	Art Unit
Paul D. Kim	3729

	SEARCHED					
Class	Subclass	Date	Examiner			
29	603.11 603.13- 603.16 603.18	7/5/2005	PK			
360	121 122	7/5/2005	PK			
	126 317					
427	127 128	- ↓				
204	192.32- 19	7/5/2005	PK			
216	22	V				
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Reviewed Parent Application 09/150,206 (US PAT. 6,188,544) 09/734,758 (ABN)	7/5/2005	PK		
Textr Search EAST/NPL (IEEE)	7/6/2005	PK		
Updated Text Search (EAST)	11/14/2005	PK		
Updated Text Search EAST	3/14/2006	PK		
Updated Text Search EAST	5/31/2006	PK		
Updated Text Search EAST/PGPub	11/21/2006	PK		